

Enhancement Mode N-Channel Power MOSFET

PDFN5X6/NMOS/20V/ \pm 12V/0.7V/110A/2.0m Ω

Rev_{0.6}





20V, $2.0m\Omega$, 110A, N-Channel MOSFET

1.Features

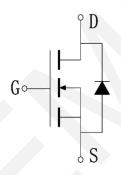
- ◆ 20V MOSFET technology
- ◆ Low on-state resistance
- Fast switching
- ♦ Vgs±12V

2.Ap	pli	cat	tio	ns
------	-----	-----	-----	----

- ◆ Power Switching Application
- Load Switching



V _{DS}	R _{DS(on)} Typ.	I _D Max.
001/	2.0mΩ @ 4.5V	4404
20V	2.7mΩ @ 2.5V	110A



Schematic Diagram

3. Package Marking and Ordering Information

Part no.	Marking	Package PCS/Reel		PCS/CTN.	
WP20H50KPA	WP20H50KPA	PDFN5X6	5,000	5,0000	

4.Absolute Max Ratings at Ta=25°C (Note1)

Parameter	Symbol	Maximum	Units
Drain to Source Voltage	V_{DSS}	20	V
Gate to Source Voltage	V_{GSS}	±12	V
Drain Current (DC)	I_{D}	110	Α
Drain Current (Pulse), PW≤300µs	I _{DP}	440	Α
Total Dissipation	P_{D}	83	W
Avalanche Energy, Single Pulsed	E _{AS}	380	mJ
Junction Temperature	Tj	150	°C
Storage Temperature	T_{stg}	-55 to +150	°C

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.



5. Thermal Resistance Ratings

Parameter	Symbol	Value	Unit
Junction to case	R _{eJC}	1.8	°C/W

Note 2: When mounted on 1 inch square copper board $t \le 10$ sec The value in any given application depends on the user's specific board design.

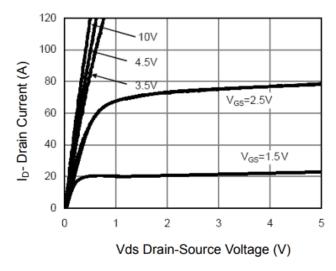
6.Electrical Characteristics at Ta=25°C (Note 3)

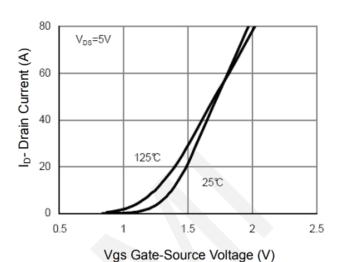
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Units
Drain to Source Breakdown Voltage	V _{(BR)DSS}	I _D = 250μA, V _{GS} = 0V	20	21.5	-	V
Zero-Gate Voltage Drain Current	I _{DSS}	V _{DS} = 20V, V _{GS} = 0V	-	-	1	uA
Gate to Source Leakage Current	I _{GSS}	$V_{GS} = \pm 12V, V_{DS} = 0V$	-	-	±100	nA
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} , I _{DS} =250μA	0.5	0.7	1.2	V
Static Drain to Source On-State	_	I _D = 20A, V _{GS} = 4.5V	-	2.0	3.0	mΩ
Resistance	R _{DS(on)}	I _D = 10A, V _{GS} = 2.5V	-	2.7	5.0	mΩ
Forward Transconductance	G _{FS}	I _D = 20A, V _{DS} = 5V	20	-	-	S
Input Capacitance	C _{iss}	V _{GS} =0V,	-	4098	-	pF
Output Capacitance	Coss	V _{DS} =10V,	-	1519	-	pF
Reverse Transfer Capacitance	C _{rss}	Frequency=1.0MHz	-	1238	-	pF
Turn-ON Delay Time	t _{d(on)}		-	6	-	ns
Rise Time	t _r	$V_{DD} = 10V, I_D = 20A,$	-	4	-	ns
Turn-OFF Delay Time	$t_{d(off)}$	$V_{GS} = 10V$, $R_{GEN} = 2.7\Omega$	-	31	-	ns
Fall Time	t _f	- 1 5 <u>C</u> N - 11 55	-	5	-	ns
Total Gate Charge	Qg	$V_{DS} = 10V,$ $V_{GS} = 4.5V,$ $I_{D} = 20A$	-	15	-	nC
	Q _{gs}		-	3	-	nC
	Q _{gd}		-	4	-	nC
Diode Forward Voltage	V _{FSD}	I _S = 20A, V _{GS} = 0	0.5	0.8	1.2	V

Note 3: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

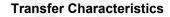


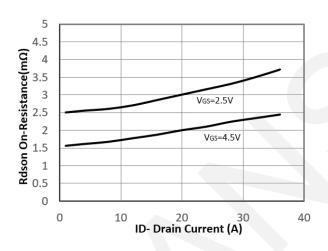
7. Typical electrical and thermal characteristics

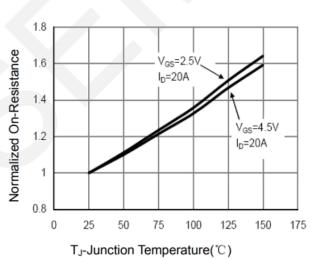




Output Characteristics

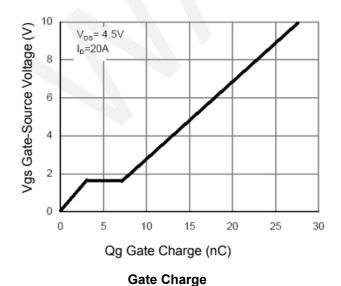


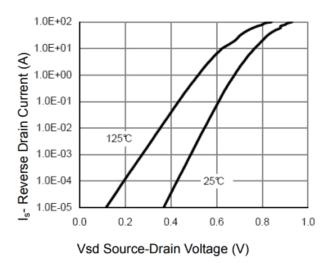




Rdson-Drain Current

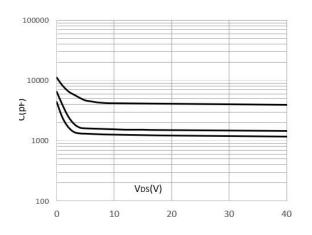
Rdson-Junction Temperature

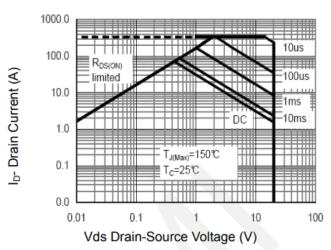




Source-Drain Diode Forward

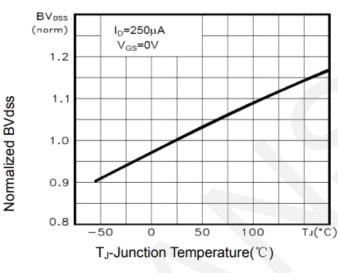


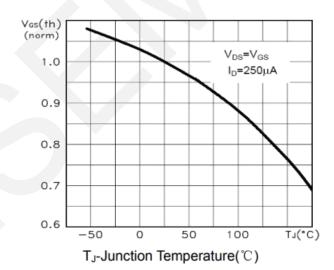




Capacitance vs Vds

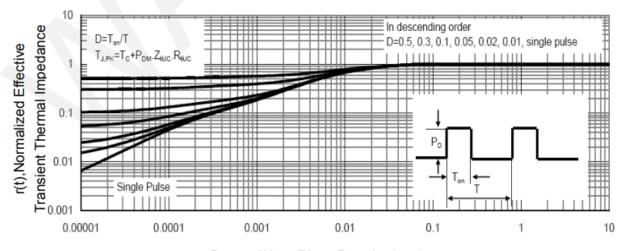
Safe Operation Area





BV_{DSS} vs Junction Temperature

 $V_{GS(th)}$ vs Junction Temperature

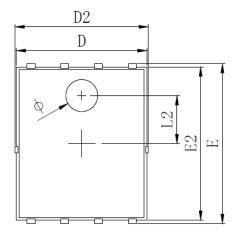


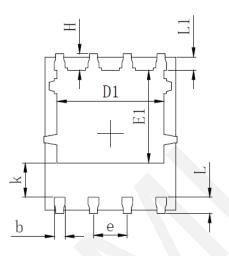
Square Wave Pluse Duration(sec)

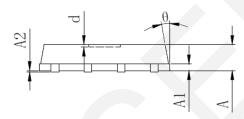
Normalized Maximum Transient Thermal Impedance



8.Package Dimensions







SYMBOL	MILLIMETER			
SIMDOL	MIN	Тур.	MAX	
A	0. 900	1.000	1. 100	
A1		0.254 REF.		
A2		0~0.05		
D	4. 824	4. 900	4. 976	
D1	3. 910	4. 010	4. 110	
D2	4. 924	5. 000	5. 076	
Е	5. 924	6. 000	6.076	
E1	3. 375	3. 475	3. 575	
E2	5. 674	5. 750	5. 826	
ъ	0. 350	0. 400	0.450	
е	1.270 TYP.			
L	0. 534	0. 610	0.686	
L1	0. 424	0. 500	0. 576	
L2	1.800 REF.			
k	1. 190	1. 290	1. 390	
Н	0. 549	0. 625	0. 701	
θ	8°	10°	12°	
ф	1. 100	1. 200	1.300	
d			0. 100	



9. Important Notice

WAN SEMICONDUCTOR (NINGBO) CO.,LTD reserves the right to make corrections, enhancements, improvements and other changes to its semiconductor products and services and to discontinue any product or service. Buyers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All semiconductor products (also referred to herein as "components") are sold subject to WANSEMI's terms and conditions of sale supplied at the time of order acknowledgment.

WANSEMI warrants performance of its components to the specifications applicable at the time of sale, in accordance with the warranty in WANSEMI's terms and conditions of sale of semiconductor products. Testing and other quality control techniques are used to the extent WANSEMI deems necessary to support this warranty. Except where mandated by applicable law, testing of all parameters of each component is not necessarily performed.

WANSEMI assumes no liability for applications assistance or the design of Buyers' products. Buyers are responsible for their products and applications using WANSEMI components. To minimize the risks associated with Buyers' products and applications, Buyers should provide adequate design and operating safeguards.

No WANSEMI components are authorized for use in FDA Class III (or similar life-critical medical equipment) unless authorized officers of the parties have executed a special agreement specifically governing such use.

Unless WANSEMI has specifically designated certain components which meet ISO/TS16949 requirements, mainly for automotive use, WANSEMI will not be responsible for any failure of such components to meet such requirements.